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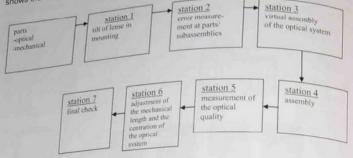


Figure 5 Flow chart of the laboratory

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# Novel Precison Positioning System with Integrated Planar

The main goal was the miniaturisation of a planar driver. This paper.

The main goal was the miniaturisation of a planar drive that has a travel range and a precision of 100 nm at all positions and to systems.

of Ø 20 mm and a precision of 100 nm at all positions and is moreover capable to of \$20 of the art lead to a variety of new concerning workshops and inquests on the state of the art lead to a variety of new concepts and solutions. For the first on the standard subsystems (magnets and coils, optical measuring unit, 3 ball to plane guides) on a granite plate was chosen (see figure 1).

The precision of a planar electrodynamic drive heavily depends on the coils, the position measurement system and guidances.

The so called "Faltflex" technology enables the manufacturing of very flat coils based on lithographical structure definition. Such coils are basically folded polymer foils with conducting copper structures, which approving high ampacity.

In order to perform closed-loop controlled motions and positioning tasks, a high precision measuring grid and an optical detector were implemented in the z-plane of the actuator

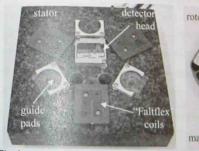




Fig. 1; open system (left - stator with guides and coils, right - rotor with magnets)

The key factor for slide bearing based systems is the material selection for the friction contact. Several material combinations consisting of Si, SiO<sub>2</sub>, Si<sub>3</sub>N<sub>4</sub>, TiN, CrN, as well as several configurations of DLC, have been tested for this purpose. Wear tests in a microtribometer and subsequent analytical evaluations of the abrasion tracks led to DLC about an optical axis had the same lacks, as well as the image of the point laying on an axis of about an optical axis had the same lacks, as well as the image of the point laying on an axis of about an optical details the decision.

system. The condition it refers to as a condition of isoplanatics, about an option of the refers to as a construction of optical details the designer "fulfils" real process of at purpose of admissions for manufacturing of optical details are eliminated to the respective when lacks of manufacturing of optical details are eliminated to the respective when lacks of manufacturing of optical details are eliminated to the respective when lacks of manufacturing of optical details are eliminated to the respective when lacks of manufacturing of optical details are eliminated to the respective when lacks of manufacturing of optical details are eliminated to the respective when lacks of manufacturing of optical details are eliminated to the respective when lacks of manufacturing of optical details are eliminated to the respective when lacks of manufacturing of optical details are eliminated to the respective when lacks of manufacturing of optical details are eliminated to the respective when lacks of manufacturing of optical details are eliminated to the respective when lacks of manufacturing of optical details are eliminated to the respective when lacks of manufacturing of optical details are eliminated to the respective when lacks of manufacturing of optical details are eliminated to the respective when lacks of manufacturing of optical details are eliminated to the respective when lacks of manufacturing of optical details are eliminated to the respective when lacks of the respective when At purpose of admissions for manufacturing of optical details are eliminated by assembly of a microobjective when lacks of manufacturing of optical details are eliminated by assembly of a microobjective when lacks of manufacturing of optical details are eliminated by assembly of a microobjective when laural assembly of a microobjective which limits of change are control to a working piece of a microobjective which limits of change are course. change of a correctional air intervals, one of which forward free working piece of a microobjective which limits of change are coordinated to of which forward free working piece of a microobjective which limits of change are coordinated to of which forward free working piece or which forward free working aperture. Changing the correctional electronic depth of the sharpness dependent on the working aperture. Changing the correctional electronic depth of the sharpness dependent on the working aperture. its depth of the sharpness dependence and making refocusing on object, the collector achieves interval appointed by the designer, and making refocusing on object, the collector achieves interval appointed by the designer, and making refocusing on object, the collector achieves interval appointed by the designor, and after check of passage of the minimal (on his subjective concept) a spherical aberration, and after check of passage of the working aperture considers, that the objective is ready.

working aperture considers, that the working aperture considers and aperture considers with the working aperture considers and aperture to optical circuits of microobjectives it is possible to use components with beforehand known dimensional and aberrational properties.

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As a result of the lead researches of face-to-face components the following conclusions are

- 1. The basic components, special aberrational correction for an opportunity of control including with use of elements ASM, face-to-face components of microobjectives are
- 2. At calculation of frontal components important that condition Abbe was observed socalled, i.e. isoplanatics value should be minimal.
- 3. The original objective specially designed for the control of frontal components of microobjectives, has the following characteristics: V =-10x S =-8 mm A=0.45.

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## Laboratory for automated assembly of microscope lenses

Section 5.1 Precision & Optical Engineering

Section.

Section.

This paper is about the concept of a laboratory for the automated assembly, verification, the distribution of barrelled microscope lenses under batch profusition. This paper is about the microscope lenses under batch production conditions, and adjustment of barrelled microscope lenses under batch production conditions. This persuance of the "Virtual Assembly Method". The amplitude in the development of the "Virtual Assembly Method". The amplitude in the development of the "Virtual Assembly Method". The amplitude in the development of the "Virtual Assembly Method". and any efforts the "Virtual Assembly Method". The employment of the "Virtual Assembly Method". The employment of this well as in the development of the "Virtual Assembly Method". The employment of this well as in the assembly process of unified microscopic lenses opens of the optical quality. prepar in the developing the optical quality at unchanged high level method to the while keeping the optical quality at unchanged high level,

needs and subassemblies is a challenging task since multiple and optoelectronic The automation of subassemblies is a challenging task since multiple error sources are components and subassemblies used to the commonly ambitious quality standards. comported to the commonly ambitious quality standards influential to the commonly ambitious quality standards

influential to the continuous of the optical characteristics as well as geometrical variations of in particular deviations of the optical characteristics as well as geometrical variations of in particular and mechanical parts have a strong impact,

the optical and the problem can not be solved or adequately delimitated by tighter in order that the associated technological and economics in order that the associated technological and economics in order than the associated technological and economics. in many cases in order that the associated technological and economical effort is not tolerances. This is in specific the case for the assembly of optical lenses, Very often is the only method to eliminate or compensate of the only method to eliminate or compensate or c affordable. Is the only method to eliminate or compensate errors in an economical adjustment is adjustment can be reduced through the analysis of the particular manner. The analysis of the particular single errors and their influence to the overall system under use of the "Virtual Assembly of the specific the automated assembly of the specific the automated assembly of the specific the specific the automated assembly of the specific th single errors are the automated assembly of microscope lenses is highly Method". In specific the automated assembly of microscope lenses is highly demands to the optical quality. Following Abbe the optical resolution s is determined by demands to wavelength  $\lambda$  and the aperture A ( $\epsilon = \lambda$  /(2A). Figure 1 shows the layout of a microscope lens of a novel unified design with a high percentage of unified elements.

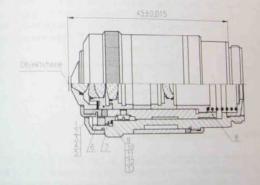


Figure 1 Layout of a microscope lens of a unified design

The correction of the spherical aberration of all elements caused by deviations in the index of refraction ( $\Delta n_{\rm el}$ ), vertex thickness ( $\Delta d$ ), the air gap ( $\Delta f$ ) and the refractive index of refraction ( $\Delta n_{\rm el}$ ), vertex thickness ( $\Delta d$ ), the air gap ( $\Delta f$ ) and the number of spacers radius( $\Delta f$ ) is done up to now manually by iterative variation of the number of spacers radius( $\Delta f$ ) is done up to now manually by iterative wounting and dismounting (Position 1-5). That results in a time and labour intensive mounting length for minimized process. Applying the "Virtual Assembly Method" the tuning length for minimized process. Applying the "Virtual Assembly a mathematical model hence the assembly spherical aberration can be calculated in a mathematical deviations of all elements need to be can be done in one step. The mentioned critical deviations of all elements need to be can be done in one step. The mentioned critical deviations of all elements need to be can be done in one step. The mentioned critical deviations of all elements need to be can be done in one step. The mentioned critical deviations of all elements need to be can be done in one step. The mentioned critical deviations of all elements need to be can be done in one step. The mentioned critical deviations of all elements need to be can be done in one step.

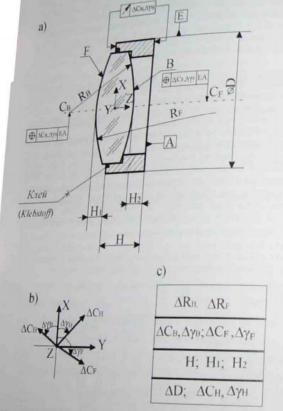
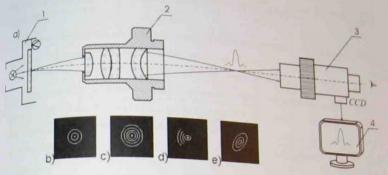


Figure 2 Critical deviations at a single mounted lens

The residual decentration of all optical subgroups to the barrel cylinder (#8, Figure 1) generates coma that classically derives compensation by a lateral shift of subassembly #6 after completion of the mounting process. This lateral movement can be done through a borehole in cylinder #8. The adjustment process can be avoided in a similar way as described for the spherical aberration. It needs the preliminary determination of

the decentration of all optical surfaces and utilisation of the "Virtual Assembly Method". The mathematical model used for this purpose allows the determination of the mounting orientation of each subgroup individually. Figure 2b shows the parameters to be orientation of A precondition for the utilisation of the method is a tolerance calculation of the whole optical system that guaranties that the residual errors are small enough the final check of the optical quality is done by the diffractive image of the lens under use of a CCD- matrix (Figure 3)



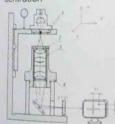
recend: 1 illuminated pinhole, 2 microscope lens, 3 frame grabber, 4 computer

Figure 3 a) Scheme of the check setup b)-e) typical diffractive images

Information's about the optical quality can be derived from the analysis of the Point Spread Function (PSF). Types and quantities of the residual optical aberrations can be identified. Is the optical quality in accordance with the expectation the next step can be taken.

The mechanical standard length (distance in-between the object plane and the mounting surface (A, Figure 1) and the centration of the optical system needs to be adjusted. In difference to the common way of the correction by machining the mounting surface to the dedicated length in centered state the new design allows the adjustment by a linear shift( given by a spacer #9- #13) and rotation of the cylinder #8.

Figure 4 shows the principle of a setup to measure standardised mechanical length and centration



Legend: 1 illuminated reticle, 2-4 microscope lens

Figure 4 Principle of the measuring set up